



Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-332001	Application No. 10/659,060
Information Disclosure Statement by Applicant (Use several sheets if necessary)  (37 CFR 1.98(b))		Applicant Peter J. de Groot	
		Filing Date September 9, 2003	Group Art Unit 2877

## U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
mjd	AA	4,999,014	03/12/1991	Gold et al.	356	382	
mjd	AB	5,133,601	07/28/1992	Cohen et al.	356	359	
mjd	AC	5,602,643	02/11/1997	Barrett	356	360	
mjd	AD	6,545,763	04/08/2003	Kim et al.	356	503	
mjd	AE	6,597,460	07/22/2003	Groot et al.	356	512	
	AF						
	AG						

## Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AH							
	AI							

## Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
mjd	AJ	Dresel, Thomas et al., "Three-dimensional sensing of rough surfaces by coherence radar", <u>Applied Optics</u> , Vol. 31, No. 7, pp. 919-925 (March 1, 1992)
mjd	AK	Feke, Gilbert D. et al., "Interferometric back focal plane microellipsometry", <u>Applied Optics</u> , Vol. 37, No. 10, pp. 1796-1802 (April 1, 1998)
mjd	AL	Kim, Seung-Woo et al., "Thickness-profile measurement of transparent thin-film layers by white-light scanning interferometry", <u>Applied Optics</u> , Vol. 38, No. 28, pp. 5968-5973 (October 1, 1999)
mjd	AM	Kino, Gordon S. et al., "Mirau correlation microscope", <u>Applied Optics</u> , Vol. 29, No. 26, pp. 3775-3783 (September 10, 1990)
mjd	AN	Pelligrand, S. et al., "Mesures 3D de topographies et de vibrations a l'echelle (sub)micrometrique par microscopie optique interferometrique", <u>Proc. Club CMOI, Methodes et Techniques Optiques pour l'Industrie</u> (2002)
mjd	AO	Pluta, Maksymilian, "Advanced Light Microscopy", Vol. 3, (Elsevier, Amsterdam, 1993) pp. 265-271
mjd	AP	Rosencwaig, Allan et al., "Beam profile reflectometry: A new technique for dielectric film measurements", <u>Applied Physics Letters</u> , Vol. 60, No. 11, pp. 1301-1303 (March 16, 1992)
mjd	AQ	Sandoz, Patrick "Wavelet transform as a processing tool in white-light interferometry", <u>Optics Letters</u> , Vol. 22, No. 14, pp. 1065-1067 (July 15, 1997)
mjd	AR	Shatalin, S.V. et al., "Reflection conoscopy and micro-ellipsometry of isotropic thin film structures", <u>Journal of Microscopy</u> , Vol. 179, Part 3, pp. 241-252 (September, 1995)

Examiner Signature <i>Maurice J. Detsch</i>	Date Considered 9-19-05
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U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
mgd	AA	4,576,479	03/18/1986	Downs	356	351	
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Foreign Patent Documents or Published Foreign Patent Applications								
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							Yes	No
mgd	AE	0 397 388 A2	11/14/1990	EPO	G01B	11/06		
mgd	AF	0 549 166 A2	06/30/1993	EPO	G01B	11/06		
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	AH							
	AI							

Other Documents (include Author, Title, Date, and Place of Publication)		
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	AM	

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